



Report No. : IP91177
Issue Date : Oct-30-2002

DEGREES OF PROTECTION PROVIDED BY ENCLOSURE OF INDUSTRIAL COMPUTER

TAIWAN ELECTRIC RESEARCH & TESTING CENTER I. P. Testing Laboratory
Address : No.84, Ta an Rd., Shulin, Taipei, Taiwan, R.O.C.

Note:

1. This report applies only to the submitted sample.
2. This report is not allowed to be duplicated partially, unless approved by TERTEC, but complete copy is exclusive.

DEGREES OF PROTECTION PROVIDED BY ENCLOSURE OF
INDUSTRIAL COMPUTER

Applicant : AAEON TECHNOLOGY INC.

Applicant Address : 5F, No.135, Lane 235, Pao Chiao Rd. Hsin-Tien City, Taipei,
Taiwan, R.O.C.

Manufacturer : AAEON TECHNOLOGY INC.

Manufacturer Address : 5F, No.135, Lane 235, Pao Chiao Rd. Hsin-Tien City, Taipei,
Taiwan, R.O.C.

Sample : Industrial computer

Model : AMB-2051

Dimensions : 444 mm(H) × 336 mm(W) × 58.9 mm(D)

Serial Model : AMB-2053 · OPD-215A

Standard : IEC 60529 (2001-02)

Sampling Procedure : Sent by applicant

Sampling Date : Oct 14, 2002

Finished Date : Oct 28, 2002

Testing Engineers : Chen, Ping ; Chen, Sheng-Hsing

Test Result : The protection of enclosure of this sampler is satisfactory for IP65,
Result of test refers to page 2.

※Note : (1)Test for the submitted main sample only.

(2)The test report is dedicated for front panel which is under "PANEL MOUNT" position

TERTEC



Sen-Lin Lai
General Manager of Testing Department

Result of Test

1.Result of test : The protection of enclosure of industrial computer is satisfactory for IP65.

2. Description of Test :

| Test Items | Standards of Test | Result of Test |
|--|---|--------------------------------|
| Degrees of protection against access to hazardous parts. Degrees of protection Against Solid Foreign Objects. First characteristic numeral 6 | IEC 60529(1989) Sec. 11.4 Sec. 13.1 Sec. 13.4 Sec. 13.5 Sec. 13.6 | The protection is satisfactory |
| Degrees of protection against water. second characteristic numeral 5 | IEC 60529(1989) Sec. 14.1 Sec. 14.2 Sec. 14.3 Sec. 14.2.5 | The protection is satisfactory |

3. View of the test sample

